



June 2004

FDP047AN08A0 / FDI047AN08A0 / FDH047AN08A0

N-Channel PowerTrench[®] MOSFET
75V, 80A, 4.7mΩ

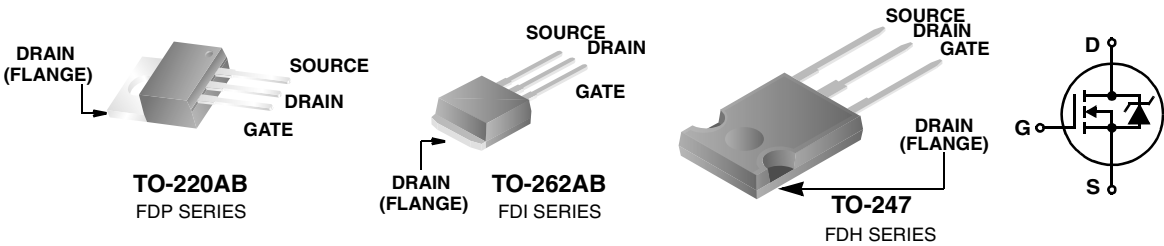
Features

- $r_{DS(ON)} = 4.0m\Omega$ (Typ.), $V_{GS} = 10V$, $I_D = 80A$
- $Q_g(tot) = 92nC$ (Typ.), $V_{GS} = 10V$
- Low Miller Charge
- Low Q_{RR} Body Diode
- UIS Capability (Single Pulse and Repetitive Pulse)
- Qualified to AEC Q101

Formerly developmental type 82684

Applications

- 42V Automotive Load Control
- Starter / Alternator Systems
- Electronic Power Steering Systems
- Electronic Valve Train Systems
- DC-DC converters and Off-line UPS
- Distributed Power Architectures and VRMs
- Primary Switch for 24V and 48V systems



MOSFET Maximum Ratings $T_C = 25^\circ C$ unless otherwise noted

Symbol	Parameter	Ratings	Units
V_{DSS}	Drain to Source Voltage	75	V
V_{GS}	Gate to Source Voltage	± 20	V
I_D	Drain Current		
	Continuous ($T_C < 144^\circ C$, $V_{GS} = 10V$)	80	A
	Continuous ($T_C = 25^\circ C$, $V_{GS} = 10V$, with $R_{\theta JA} = 62^\circ C/W$)	15	A
	Pulsed	Figure 4	A
E_{AS}	Single Pulse Avalanche Energy (Note 1)	475	mJ
P_D	Power dissipation	310	W
	Derate above $25^\circ C$	2.0	W/ $^\circ C$
T_J, T_{STG}	Operating and Storage Temperature	-55 to 175	$^\circ C$

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance Junction to Case TO-220, TO-262, TO-247	0.48	$^\circ C/W$
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-220, TO-262 (Note 2)	62	$^\circ C/W$
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-247 (Note 2)	30	$^\circ C/W$

This product has been designed to meet the extreme test conditions and environment demanded by the automotive industry. For a copy of the requirements, see AEC Q101 at: <http://www.aecouncil.com/>

All Fairchild Semiconductor products are manufactured, assembled and tested under ISO9000 and QS9000 quality systems certification.

FDP047AN08A0 / FDI047AN08A0 / FDH047AN08A0

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP047AN08A0	FDP047AN08A0	TO-220AB	Tube	N/A	50 units
FDI047AN08A0	FDI047AN08A0	TO-262AB	Tube	N/A	50 units
FDH047AN08A0	FDH047AN08A0	TO-247	Tube	N/A	30 units

Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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Off Characteristics

B_{VDSS}	Drain to Source Breakdown Voltage	$I_D = 250\mu\text{A}$, $V_{GS} = 0\text{V}$	75	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 60\text{V}$ $V_{GS} = 0\text{V}$ $T_C = 150^\circ\text{C}$	-	-	1	μA
I_{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20\text{V}$	-	-	± 100	nA

On Characteristics

$V_{GS(TH)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 250\mu\text{A}$	2	-	4	V
$r_{DS(ON)}$	Drain to Source On Resistance	$I_D = 80\text{A}$, $V_{GS} = 10\text{V}$	-	0.0040	0.0047	Ω
		$I_D = 37\text{A}$, $V_{GS} = 6\text{V}$	-	0.0058	0.0087	
		$I_D = 80\text{A}$, $V_{GS} = 10\text{V}$, $T_J = 175^\circ\text{C}$	-	0.0082	0.011	

Dynamic Characteristics

C_{ISS}	Input Capacitance	$V_{DS} = 25\text{V}$, $V_{GS} = 0\text{V}$, $f = 1\text{MHz}$	-	6600	-	pF
C_{OSS}	Output Capacitance		-	1000	-	pF
C_{RSS}	Reverse Transfer Capacitance		-	240	-	pF
$Q_{g(TOT)}$	Total Gate Charge at 10V	$V_{GS} = 0\text{V}$ to 10V	-	92	138	nC
$Q_{g(TH)}$	Threshold Gate Charge	$V_{GS} = 0\text{V}$ to 2V	-	11	17	nC
Q_{gs}	Gate to Source Gate Charge	$V_{DD} = 40\text{V}$ $I_D = 80\text{A}$ $I_g = 1.0\text{mA}$	-	27	-	nC
Q_{gs2}	Gate Charge Threshold to Plateau		-	16	-	nC
Q_{gd}	Gate to Drain "Miller" Charge		-	21	-	nC
			-			

Switching Characteristics ($V_{GS} = 10\text{V}$)

t_{ON}	Turn-On Time	$V_{DD} = 40\text{V}$, $I_D = 80\text{A}$ $V_{GS} = 10\text{V}$, $R_{GS} = 3.3\Omega$	-	-	160	ns
$t_{d(ON)}$	Turn-On Delay Time		-	18	-	ns
t_r	Rise Time		-	88	-	ns
$t_{d(OFF)}$	Turn-Off Delay Time		-	40	-	ns
t_f	Fall Time		-	45	-	ns
t_{OFF}	Turn-Off Time		-	-	128	ns

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Voltage	$I_{SD} = 80\text{A}$	-	-	1.25	V
		$I_{SD} = 40\text{A}$	-	-	1.0	V
t_{rr}	Reverse Recovery Time	$I_{SD} = 75\text{A}$, $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	-	53	ns
Q_{RR}	Reverse Recovered Charge	$I_{SD} = 75\text{A}$, $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	-	54	nC

Notes:

- 1: Starting $T_J = 25^\circ\text{C}$, $L = 0.232\text{mH}$, $I_{AS} = 64\text{A}$.
2: Pulse Width = 100s

Typical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

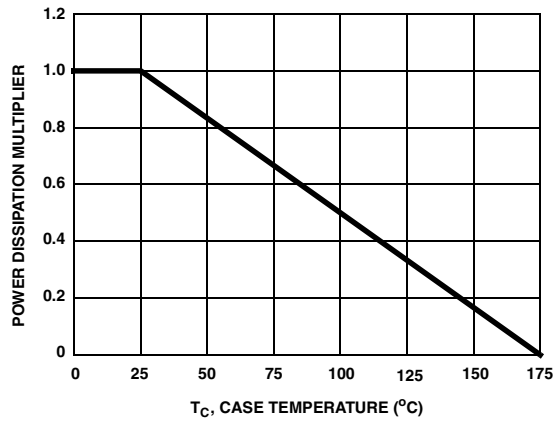


Figure 1. Normalized Power Dissipation vs Case Temperature

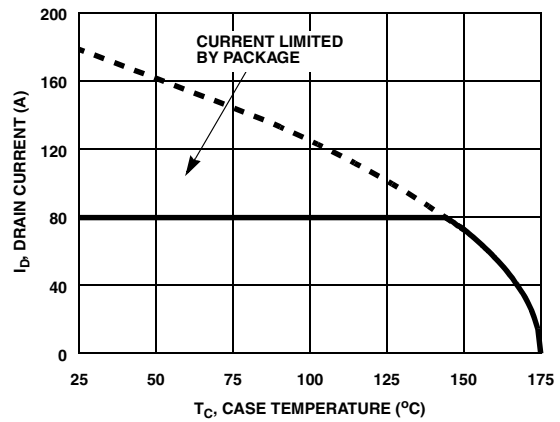


Figure 2. Maximum Continuous Drain Current vs Case Temperature

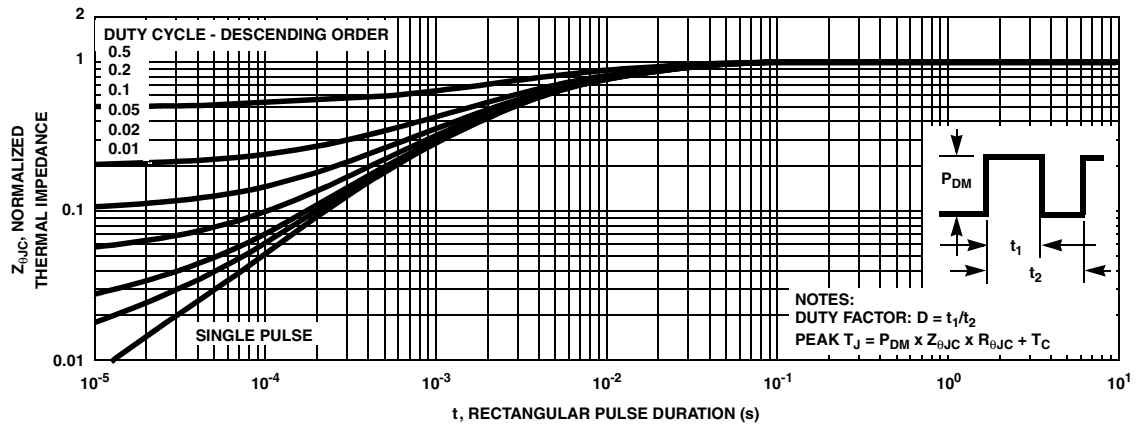


Figure 3. Normalized Maximum Transient Thermal Impedance

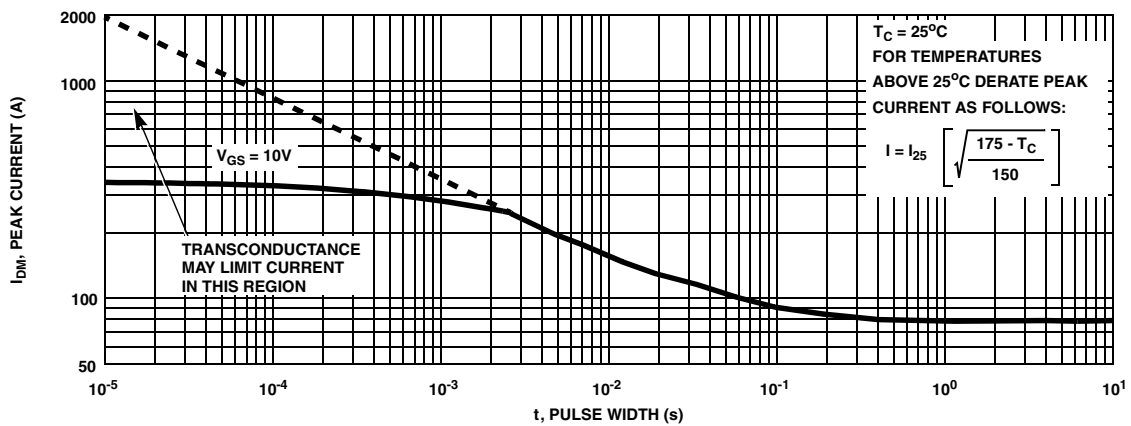


Figure 4. Peak Current Capability

Typical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

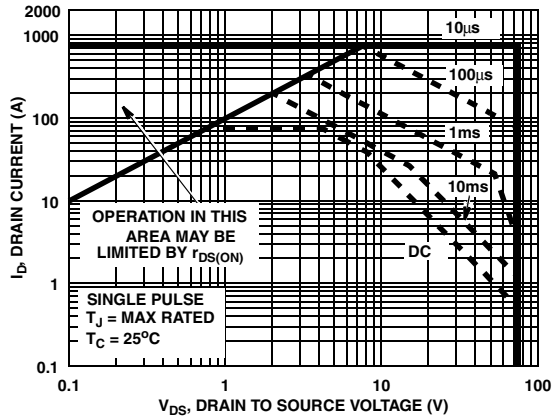
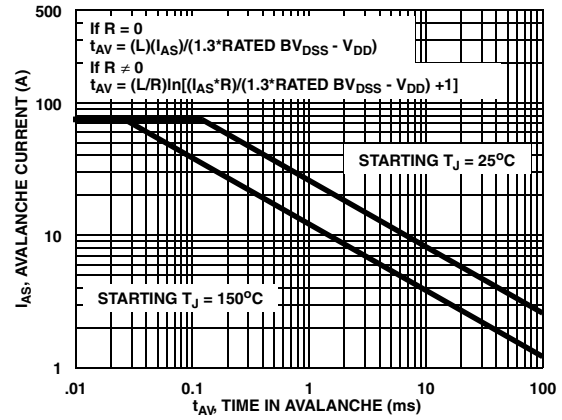


Figure 5. Forward Bias Safe Operating Area



NOTE: Refer to Fairchild Application Notes AN7514 and AN7515
Figure 6. Unclamped Inductive Switching Capability

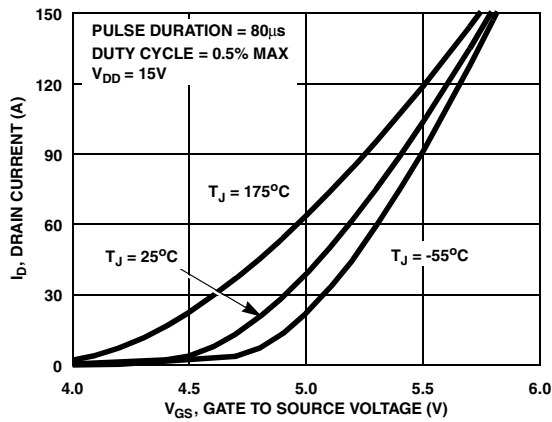


Figure 7. Transfer Characteristics

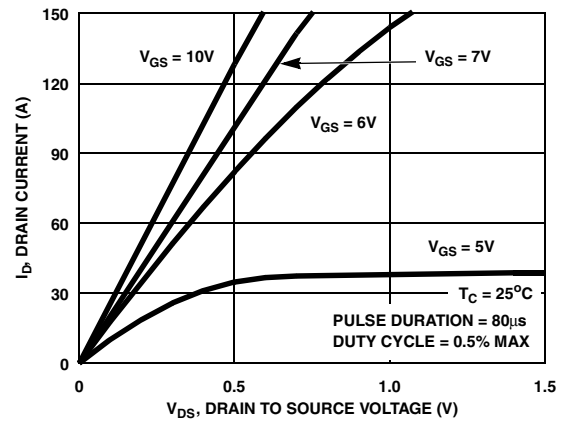


Figure 8. Saturation Characteristics

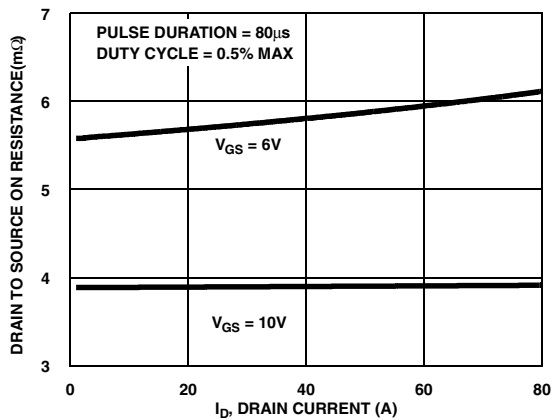


Figure 9. Drain to Source On Resistance vs Drain Current

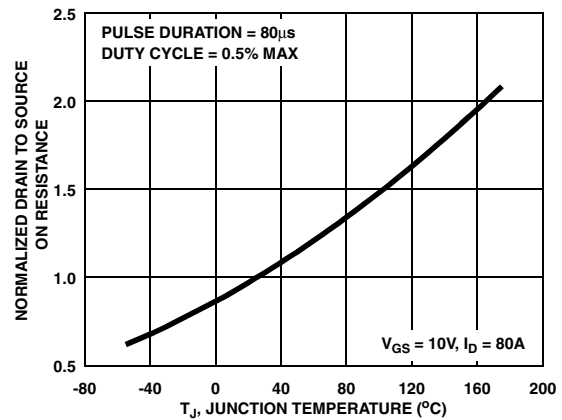


Figure 10. Normalized Drain to Source On Resistance vs Junction Temperature

Typical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

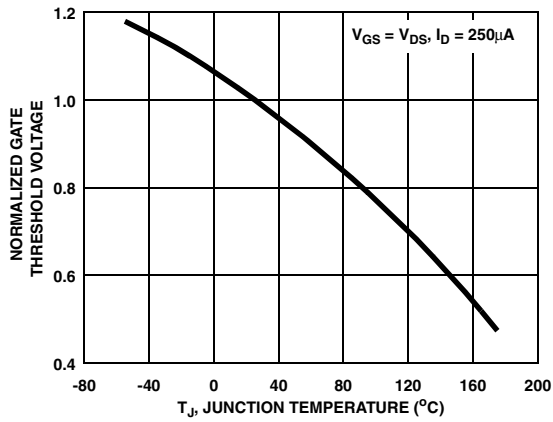


Figure 11. Normalized Gate Threshold Voltage vs Junction Temperature

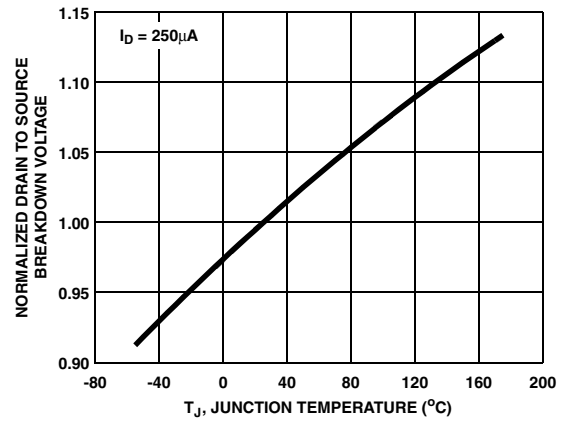


Figure 12. Normalized Drain to Source Breakdown Voltage vs Junction Temperature

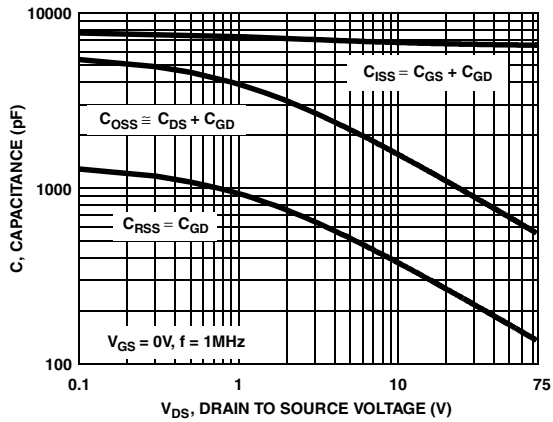


Figure 13. Capacitance vs Drain to Source Voltage

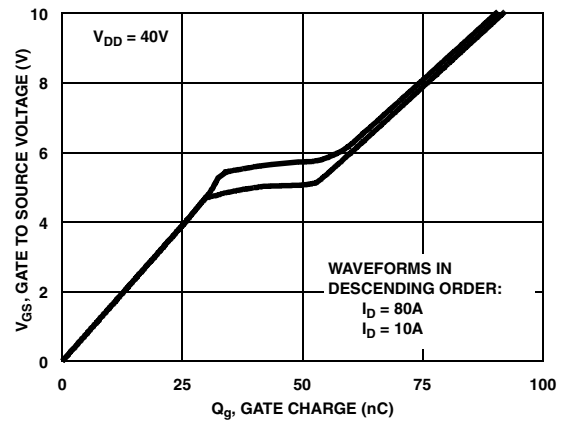


Figure 14. Gate Charge Waveforms for Constant Gate Currents

Test Circuits and Waveforms

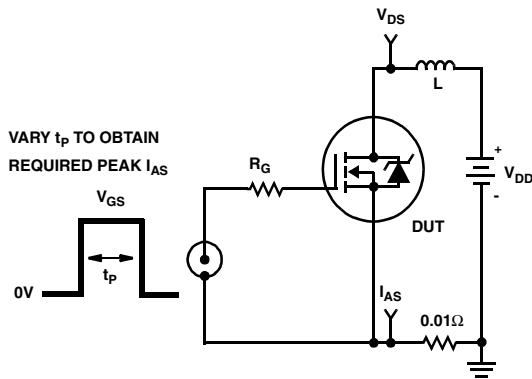


Figure 15. Unclamped Energy Test Circuit

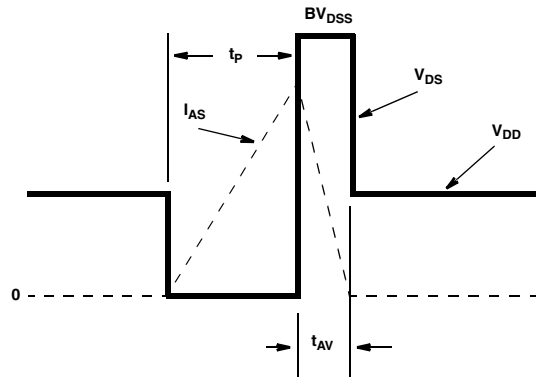


Figure 16. Unclamped Energy Waveforms

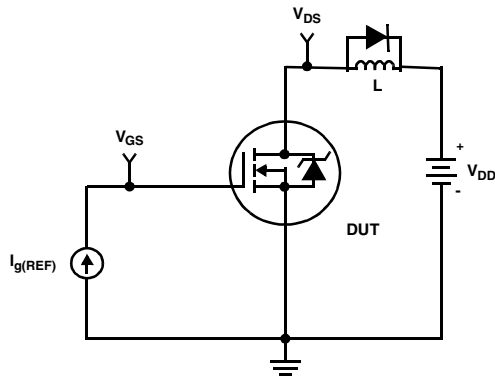


Figure 17. Gate Charge Test Circuit

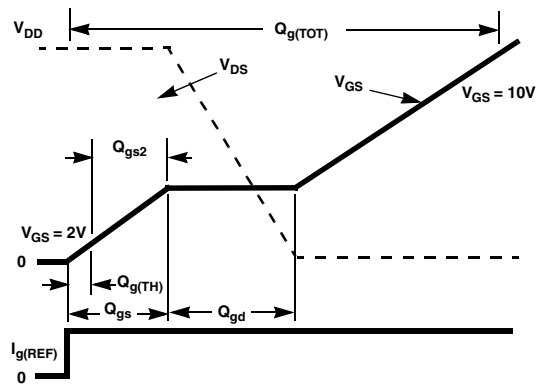


Figure 18. Gate Charge Waveforms

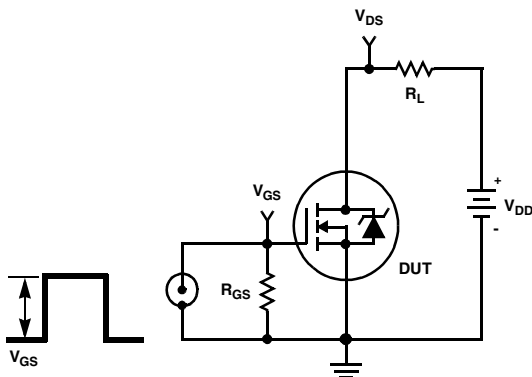


Figure 19. Switching Time Test Circuit

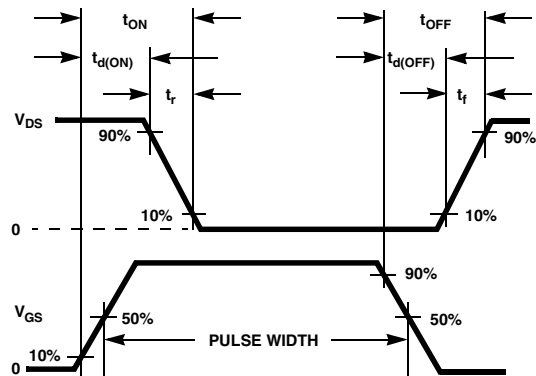


Figure 20. Switching Time Waveforms

PSPICE Electrical Model

.SUBCKT FDP047AN08A0 2 1 3 ; rev March 2002

CA 12 8 1.5e-9
CB 15 14 1.5e-9
CIN 6 8 6.4e-9

DBODY 7 5 DBODYMOD
DBREAK 5 11 DBREAKMOD
DPLCAP 10 5 DPLCAPMOD

EBREAK 11 7 17 18 82.3
EDS 14 8 5 8 1
EGS 13 8 6 8 1
ESG 6 10 6 8 1
EVTHRES 6 21 19 8 1
EVTEMP 20 6 18 22 1

IT 8 17 1

LDRAIN 2 5 1e-9
LGATE 1 9 4.81e-9
LSOURCE 3 7 4.63e-9

MMED 16 6 8 8 MMEDMOD
MSTRO 16 6 8 8 MSTROMOD
MWEAK 16 21 8 8 MWEAKMOD

RBREAK 17 18 RBREAKMOD 1
RDRAIN 50 16 RDRAINMOD 9e-4
RGATE 9 20 1.36
RLDRAIN 2 5 10
RLGATE 1 9 48.1
RLSOURCE 3 7 46.3
RSLC1 5 51 RSLCMOD 1e-6
RSLC2 5 50 1e3
RSOURCE 8 7 RSOURCEMOD 2.3e-3
RVTHRES 22 8 RVTHRESMOD 1
RVTEMP 18 19 RVTEMPMOD 1

S1A 6 12 13 8 S1AMOD
S1B 13 12 13 8 S1BMOD
S2A 6 15 14 13 S2AMOD
S2B 13 15 14 13 S2BMOD

VBAT 22 19 DC 1

ESLC 51 50 VALUE={(V(5,51)/ABS(V(5,51)))*(PWR(V(5,51)/(1e-6*250),10))}

.MODEL DBODYMOD D (IS = 2.4e-11 N = 1.04 RS = 1.76e-3 TRS1 = 2.7e-3 TRS2 = 2e-7 XTI = 3.9 CJO = 4.35e-9 TT = 1e-8 M = 5.4e-1)

.MODEL DBREAKMOD D (RS = 1.5e-1 TRS1 = 1e-3 TRS2 = -8.9e-6)

.MODEL DPLCAPMOD D (CJO = 1.35e-9 IS = 1e-30 N = 10 M = 0.53)

.MODEL MMEDMOD NMOS (VTO = 3.7 KP = 9 IS = 1e-30 N = 10 TOX = 1 L = 1u W = 1u RG = 1.36)

.MODEL MSTROMOD NMOS (VTO = 4.4 KP = 250 IS = 1e-30 N = 10 TOX = 1 L = 1u W = 1u)

.MODEL MWEAKMOD NMOS (VTO = 3.05 KP = 0.03 IS = 1e-30 N = 10 TOX = 1 L = 1u W = 1u RG = 1.36e1 RS = 0.1)

.MODEL RBREAKMOD RES (TC1 = 1.05e-3 TC2 = -9e-7)

.MODEL RDRAINMOD RES (TC1 = 1.9e-2 TC2 = 4e-5)

.MODEL RSLCMOD RES (TC1 = 1.3e-3 TC2 = 1e-5)

.MODEL RSOURCEMOD RES (TC1 = 1e-3 TC2 = 1e-6)

.MODEL RVTHRESMOD RES (TC1 = -6e-3 TC2 = -1.9e-5)

.MODEL RVTEMPMOD RES (TC1 = -2.4e-3 TC2 = 1e-6)

.MODEL S1AMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = -4.0 VOFF = -1.5)

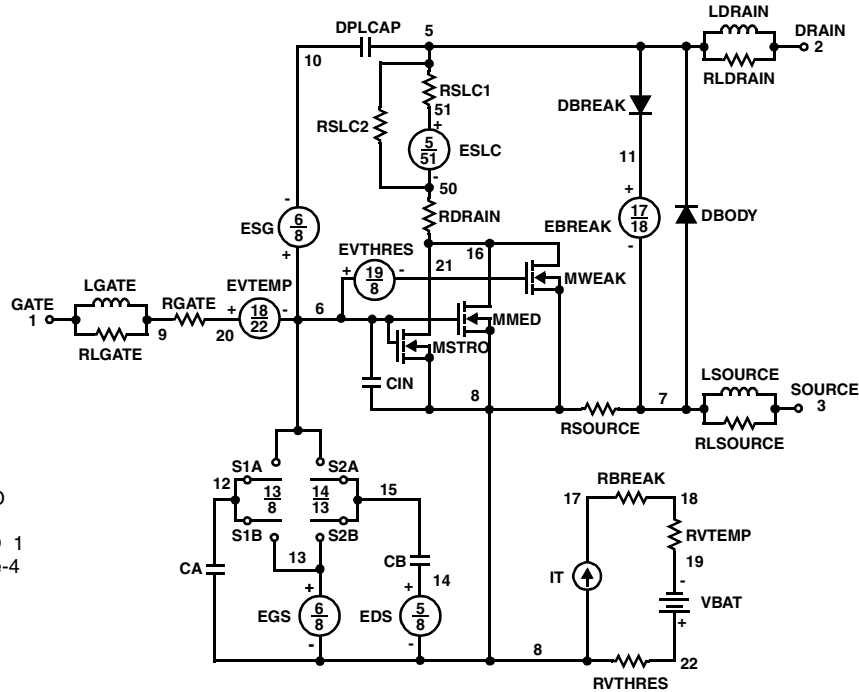
.MODEL S1BMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = -1.5 VOFF = -4.0)

.MODEL S2AMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = -1.0 VOFF = 0.5)

.MODEL S2BMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = 0.5 VOFF = -1.0)

.ENDS

Note: For further discussion of the PSPICE model, consult **A New PSPICE Sub-Circuit for the Power MOSFET Featuring Global Temperature Options**; IEEE Power Electronics Specialist Conference Records, 1991, written by William J. Hepp and C. Frank Wheatley.



SPICE Thermal Model

REV 23 March 2002

FDP047AN08A0T

CTHERM1 th 6 6.45e-3
 CHERM2 6 5 3e-2
 CHERM3 5 4 1.4e-2
 CHERM4 4 3 1.65e-2
 CHERM5 3 2 4.85e-2
 CHERM6 2 tl 1e-1

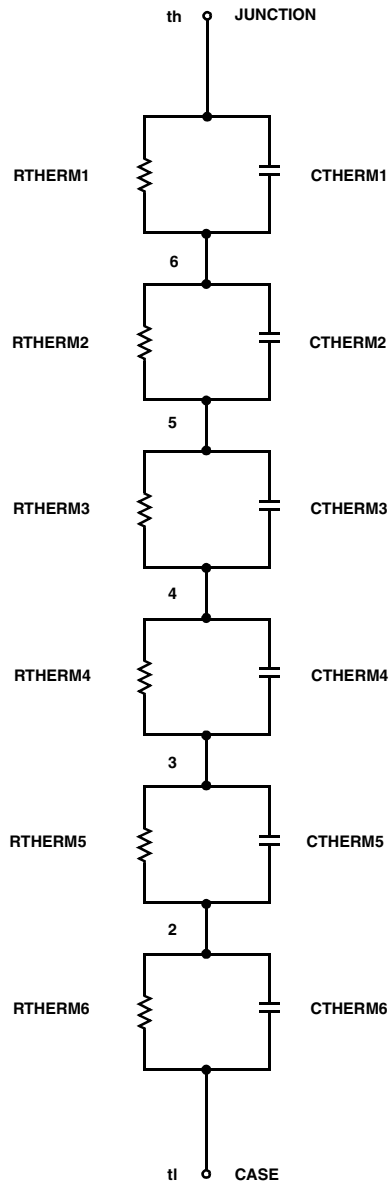
RHERM1 th 6 3.24e-3
 RHERM2 6 5 8.08e-3
 RHERM3 5 4 2.28e-2
 RHERM4 4 3 1e-1
 RHERM5 3 2 1.1e-1
 RHERM6 2 tl 1.4e-1

SABER Thermal Model

SABER thermal model FDP047AN08A0T
 template thermal_model th tl
 thermal_c th, tl

```
{
  ctherm.ctherm1 th 6 = 6.45e-3
  ctherm.ctherm2 6 5 = 3e-2
  ctherm.ctherm3 5 4 = 1.4e-2
  ctherm.ctherm4 4 3 = 1.65e-2
  ctherm.ctherm5 3 2 = 4.85e-2
  ctherm.ctherm6 2 tl = 1e-1
```

```
  rtherm.rtherm1 th 6 = 3.24e-3
  rtherm.rtherm2 6 5 = 8.08e-3
  rtherm.rtherm3 5 4 = 2.28e-2
  rtherm.rtherm4 4 3 = 1e-1
  rtherm.rtherm5 3 2 = 1.1e-1
  rtherm.rtherm6 2 tl = 1.4e-1
}
```



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CoolFET™	FPST™	MICROCOUPLER™	PowerTrench®	SuperSOT™-6
CROSSVOLT™	FRFET™	MicroFET™	QFET®	SuperSOT™-8
DOME™	GlobalOptoisolator™	MicroPak™	QS™	SyncFET™
EcoSPARK™	GTO™	MICROWIRE™	QT Optoelectronics™	TinyLogic®
E ² CMOS™	HiSeC™	MSX™	Quiet Series™	TINYOPTO™
EnSigna™	I ² C™	MSXPro™	RapidConfigure™	TruTranslation™
FACT™	i-Lo™	OCX™	RapidConnect™	UHC™
Across the board. Around the world.™		OCXPro™	μSerDes™	UltraFET®
The Power Franchise®		OPTOLOGIC®	SILENT SWITCHER®	VCX™
Programmable Active Droop™		OPTOPLANAR™	SMART START™	
		PACMAN™	SPM™	

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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
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